## Application/Control No. Applicant(s)/Patent Under Reexamination 10/564,396 TAE ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 2817 Benny Lee **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY \* US-2003/0076198 04-2003 Phillips et al. 333/161 Α US-2006/0273864 12-2006 Zimmerman et al. 333/161 В US-C US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) υ

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